### **INTEGRATED CIRCUITS**

# DATA SHEET



# 74F219A

64-bit TTL bipolar RAM, non-inverting (3-State)

Product specification

1996 Jan 05

IC15 Data Handbook





### 64-bit TTL bipolar RAM, non-inverting (3-State)

74F219A

#### **FEATURES**

- High speed performance
- Replaces 74F219
- Address access time: 8ns max vs 28ns for 74F219
- Power dissipation: 4.3mW/bit typ
- Schottky clamp TTL
- One chip enable
- Non-Inverting outputs (for inverting outputs see 74F189A)
- 3-state outputs
- 74F219A in 150 mil wide SO is preferred options for new designs
- C3F219A in 300 mil wide SOL replaces 74F219 in existing designs

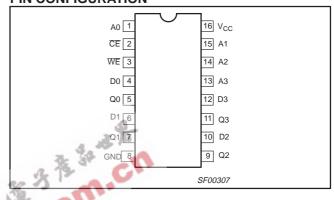
#### **DESCRIPTION**

The 74F219A is a high speed, 64–bit RAM organized as a 16–word by 4–bit array. Address inputs are buffered to minimize loading and are fully decoded on chip. The outputs are in high impedance state whenever the chip enable ( $\overline{\text{CE}}$ ) is high. The outputs are active only in the READ mode ( $\overline{\text{WE}}$  = high) and the output data is the complement of the stored data.

#### **APPLICATIONS**

- Scratch pad memory
- Buffer memory
- Push down stacks
- Control store

### **PIN CONFIGURATION**



TYPE	TYPICAL ACCESS TIME	TYPICAL SUPPLY CURRENT(TOTAL)
74F219A	5.0ns	55mA

### ORDERING INFORMATION

	ORDER CODE	
DESCRIPTION	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$ , $T_{amb} = 0^{\circ}C$ to $+70^{\circ}C$	DRAWING NUMBER
16-pin plastic Dual In-line Package	N74F219AN	SOT38-4
16-pin plastic Small Outline (150mil)	N74F219AD	SOT109-1
16-pin plastic Small Outline Large (300mil)	C3F219AD	SOT162-1

#### INPUT AND OUTPUT LOADING AND FAN OUT TABLE

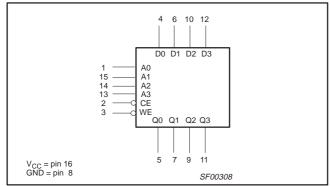
017	1 20/10/11/0 / 1/11/0 0 1 1/10/22		
PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
D0 – D3	Data inputs	1.0/1.0	20μA/0.6mA
A0 – A3	Address inputs	1.0/1.0	20μA/0.6mA
CE	Chip enable input (active low)	1.0/2.0	20μA/1.2mA
WE	Write enable input (active low)	1.0/2.0	20μA/1.2mA
Q0 – Q3	Data outputs	150/40	3mA/24mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the high state and 0.6mA in the low state.

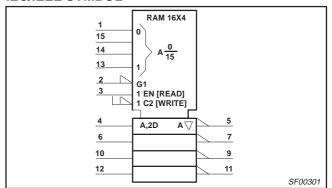
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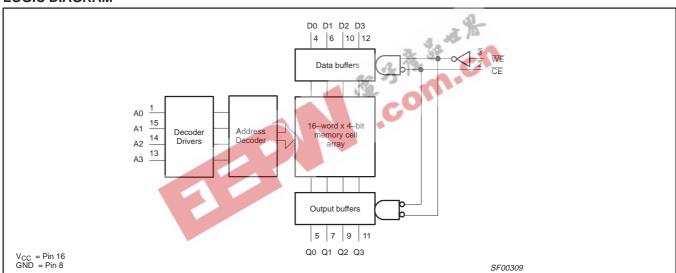
### **LOGIC SYMBOL**



### **IEC/IEEE SYMBOL**



### **LOGIC DIAGRAM**



### **FUNCTION TABLE**

l l	NPUTS	3	OUTPUT	OPERATING
CE	WE	Dn	Q <sub>n</sub>	MODE
L	Н	Х	Stored data	Read
L	L	L	High impedance	Write "0"
L	L	Н	High impedance	Write "1"
Н	Х	Х	High impedance	Disable input

### NOTES:

H = High voltage level L = Low voltage level

X = Don't care

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#### **ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V <sub>CC</sub>	Supply voltage	-0.5 to +7.0	V
V <sub>IN</sub>	Input voltage	-0.5 to +7.0	V
I <sub>IN</sub>	Input current	-30 to +5	mA
V <sub>OUT</sub>	Voltage applied to output in high output state	–0.5 to V <sub>CC</sub>	V
I <sub>OUT</sub>	Current applied to output in low output state	48	mA
T <sub>amb</sub>	Operating free-air temperature range	0 to +70	°C
T <sub>stg</sub>	Storage temperature range	-65 to +150	°C

#### RECOMMENDED OPERATING CONDITIONS

CVMDOL	DADAMETED		LIMITS					
SYMBOL	PARAMETER	MIN	NOM	MAX	UNIT			
V <sub>CC</sub>	Supply voltage	4.5	5.0	5.5	V			
V <sub>IH</sub>	High-level input voltage	2.0			V			
$V_{IL}$	Low-level input voltage	4		0.8	V			
I <sub>lk</sub>	Input clamp current			-18	mA			
I <sub>OH</sub>	High-level output current			-3	mA			
I <sub>OL</sub>	Low-level output current			24	mA			
T <sub>amb</sub>	Operating free-air temperature range	0		+70	°C			

### DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITIONS	;1		LIMITS		UNIT
					MIN	TYP <sup>2</sup>	MAX	1
V <sub>OH</sub>	High-level output voltage		V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX	±10%V <sub>CC</sub>	2.4			V
			$V_{IH} = MIN, I_{OH} = MAX$	±5%V <sub>CC</sub>	2.7	3.4		٧
V <sub>OL</sub>	,		V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX	±10%V <sub>CC</sub>		0.35	0.50	V
			$V_{IH} = MIN, I_{OL} = MAX$	±5%V <sub>CC</sub>		0.35	0.50	V
V <sub>IK</sub>			$V_{CC} = MIN, I_I = I_{IK}$	$V_{CC} = MIN, I_I = I_{IK}$				
I <sub>I</sub>	Input current at maximum input	voltage	$V_{CC} = MAX, V_I = 7.0V$			100	μΑ	
I <sub>IH</sub>	High-level input current		$V_{CC} = MAX, V_I = 2.7V$			20	μΑ	
I <sub>IL</sub>	Low-level input current	others	$V_{CC} = MAX, V_I = 0.5V$			-0.6	mA	
		CE, WE	1			-1.2	mA	
I <sub>OZH</sub>	Offset output current, high-level voltage applied	•	$V_{CC} = MAX, V_I = 2.7V$				50	μА
I <sub>OZL</sub>	Offset output current, low–level voltage applied		$V_{CC} = MAX, V_I = 0.5V$			-50	μА	
los	Short-circuit output current <sup>3</sup> Supply current (total)		V <sub>CC</sub> = MAX		-60		-150	mA
I <sub>CC</sub>			$V_{CC} = MAX, \overline{CE} = \overline{WE} = GND$			55	80	mA
C <sub>IN</sub>	Input capacitance		$V_{CC} = 5V, V_{IN} = 2.0V$			4		pF
C <sub>OUT</sub>	Output capacitance		V <sub>CC</sub> = 5V, V <sub>OUT</sub> = 2.0V			7		pF

#### NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

2. All typical values are at  $V_{CC} = 5V$ ,  $T_{amb} = 25$ °C.

<sup>3.</sup> Not more than one output should be shorted at a time. For testing I<sub>OS</sub>, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.

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### **AC ELECTRICAL CHARACTERISTICS**

						LIM	ITS		
SYMBOL	PARA	METER	TEST CONDITION	T <sub>a</sub> V C <sub>L</sub> = 5	<sub>mb</sub> = +25 <sub>CC</sub> = +5.0 0pF, R <sub>L</sub> =	°C V = <b>500</b> Ω	T <sub>amb</sub> = 0°0 V <sub>CC</sub> = +5. C <sub>L</sub> = 50pF,	C to +70°C 0V ± 10% R <sub>L</sub> = 500Ω	UNIT
				MIN	TYP	MAX	MIN	MAX	
t <sub>PLH</sub> t <sub>PHL</sub>	Access time	Propagation delay An to Qn	Waveform 1	2.5 2.0	5.0 4.5	8.0 8.0	2.5 2.0	8.0 8.0	ns
t <sub>PZH</sub> t <sub>PZL</sub>		Enable time CE to Qn	Waveform 2	1.5 2.5	3.0 4.0	6.0 7.0	1.5 2.0	7.0 7.5	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Disable time CE to Qn		Waveform 3	2.5 1.5	4.5 3.0	7.0 5.5	2.0 1.0	8.0 6.0	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Write recovery time	Enable time WE to Qn	Waveform 4	2.0 3.0	3.5 4.5	6.5 7.5	1.5 2.5	7.0 8.0	ns
t <sub>PHZ</sub>	Disable time WE to Qn		Waveform 4	3.0 1.5	5.0 3.5	8.0 6.0	2.5 1.5	9.0 7.0	ns
AC SETUE	DECHIDEMENT			25.	32.15	h -			
AC SETUR	REQUIREMENT			2 1/2	ar d				

### **AC SETUP REQUIREMENT**

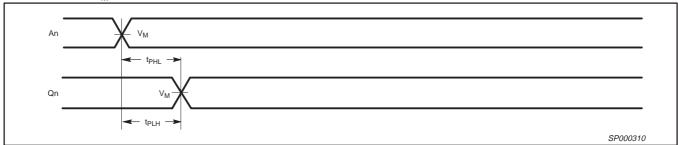
		90	3	4	LIM	ITS		
SYMBOL	PARAMETER	TEST CONDITION	C <sub>L</sub> = 5	<sub>mb</sub> = +25 <sub>CC</sub> = +5.0 0pF, R <sub>L</sub> =	°C V = 500Ω	T <sub>amb</sub> = 0°C V <sub>CC</sub> = +5. C <sub>L</sub> = 50pF,	UNIT	
			MIN	TYP	MAX	MIN	MAX	
t <sub>su</sub> (H) t <sub>su</sub> (L)	Setup time, high or low An to WE	Waveform 4	4.5 4.5			5.0 5.0		ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time, high or low An to WE	Waveform 4	0 0			0		ns
t <sub>su</sub> (H) t <sub>su</sub> (L)	Setup time, high or low Dn to WE	Waveform 4	8.0 7.5			9.0 8.5		ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time, high or low Dn to WE	Waveform 4	0 0			0 0		ns
t <sub>su</sub> (L)	Setup time, low CE (falling edge) to WE (falling edge)	Waveform 4	0			0		ns
t <sub>h</sub> (L)	Hold time, low WE (falling edge) to WE (rising edge)	Waveform 4	6.5			7.5		ns
t <sub>w</sub> (L)	Pulse width, low WE	Waveform 4	7.0			8.0		ns

# 64-bit TTL bipolar RAM, non-inverting (3-State)

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### **AC WAVEFORMS FOR READ CYCLES**

For all waveforms,  $V_M = 1.5V$ .



Waveform 1. Read cycle, address access time



Waveform 2. Read cycle, chip enable access time



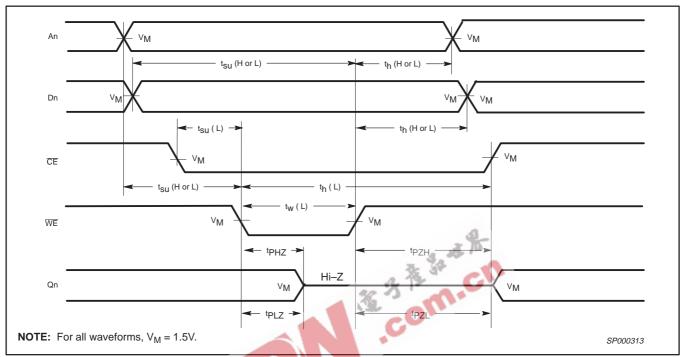
Waveform 3. Read cycle, chip disable time

### 64-bit TTL bipolar RAM, non-inverting (3-State)

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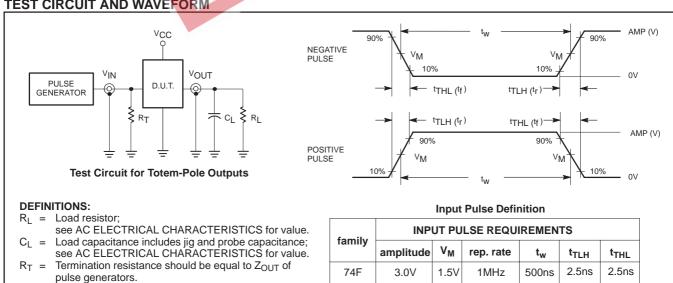
SF00006

#### **AC WAVEFORMS FOR WRITE CYCLE**



Waveform 4. Write cycle

### **TEST CIRCUIT AND WAVEFORM**

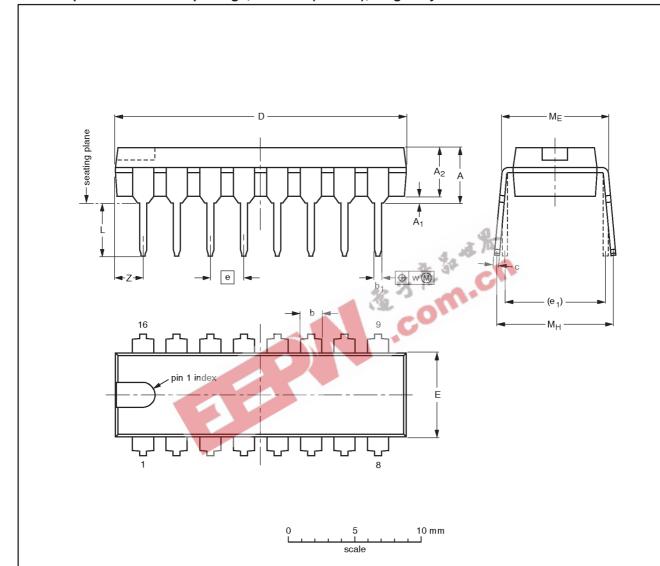


# 64-Bit TTL bipolar RAM, non-inverting (3-State)

74F219A

### DIP16: plastic dual in-line package; 16 leads (300 mil); long body

SOT38-1



### DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A <sub>1</sub> min.	A <sub>2</sub> max.	b	b <sub>1</sub>	С	D <sup>(1)</sup>	E <sup>(1)</sup>	е	e <sub>1</sub>	L	ME	M <sub>H</sub>	w	Z <sup>(1)</sup> max.
mm	4.7	0.51	3.7	1.40 1.14	0.53 0.38	0.32 0.23	21.8 21.4	6.48 6.20	2.54	7.62	3.9 3.4	8.25 7.80	9.5 8.3	0.254	2.2
inches	0.19	0.020	0.15	0.055 0.045	0.021 0.015	0.013 0.009	0.86 0.84	0.26 0.24	0.10	0.30	0.15 0.13	0.32 0.31	0.37 0.33	0.01	0.087

### Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

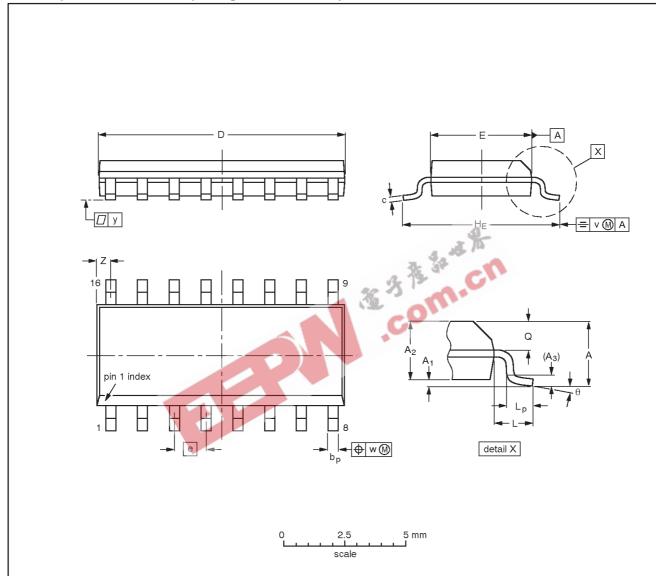
OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT38-1	050G09	MO-001AE				<del>-92-10-02-</del> 95-01-19

# 64-Bit TTL bipolar RAM, non-inverting (3-State)

74F219A

### SO16: plastic small outline package; 16 leads; body width 3.9 mm

SOT109-1



### DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	bp	С	D <sup>(1)</sup>	E <sup>(1)</sup>	е	HE	L	Lp	Q	v	w	у	Z <sup>(1)</sup>	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	10.0 9.8	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004		0.01			0.39 0.38	0.16 0.15	0.050	0.244 0.228	0.041	0.039 0.016	0.028 0.020	0.01	0.01	0.004	0.028 0.012	0°

#### Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

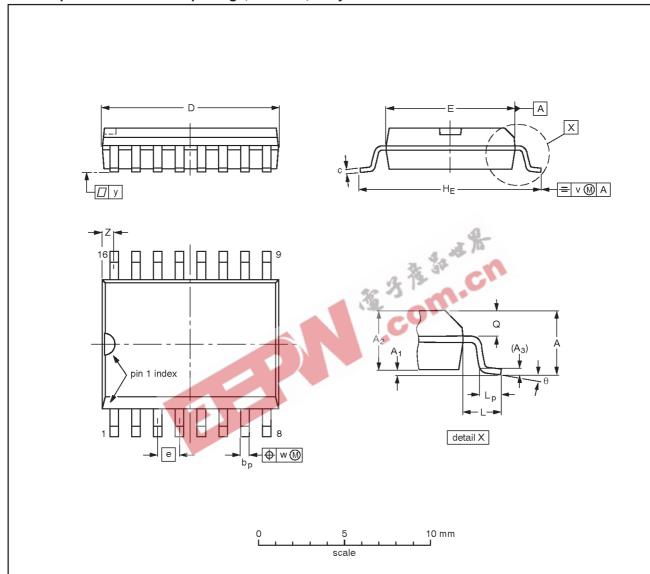
OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	EIAJ		PROJECTION	1330E DATE	
SOT109-1	076E07S	MS-012AC				<del>95-01-23</del> 97-05-22	

# 64-Bit TTL bipolar RAM, non-inverting (3-State)

74F219A

### SO16: plastic small outline package; 16 leads; body width 7.5 mm

SOT162-1



### DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	bp	С	D <sup>(1)</sup>	E <sup>(1)</sup>	е	HE	L	Lp	Q	v	w	у	z <sup>(1)</sup>	θ
mm	2.65	0.30 0.10	2.45 2.25	0.25	0.49 0.36	0.32 0.23	10.5 10.1	7.6 7.4	1.27	10.65 10.00	1.4	1.1 0.4	1.1 1.0	0.25	0.25	0.1	0.9 0.4	8°
inches	0.10	0.012 0.004	0.096 0.089	0.01	0.019 0.014	0.013 0.009	0.41 0.40	0.30 0.29	0.050	0.419 0.394	0.055	0.043 0.016	0.043 0.039	0.01	0.01	0.004	0.035 0.016	0°

#### Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ICCUE DATE			
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
SOT162-1	075E03	MS-013AA				<del>95 01 24</del> 97-05-22	

### 64-Bit TTL bipolar RAM, non-inverting (3-State)

74F219A

### **NOTES**



### 64-bit TTL bipolar RAM, non-inverting (3-State)

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DEFINITIONS						
Data Sheet Identification	Product Status	Definition				
Objective Specification	Formative or in Design	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.				
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